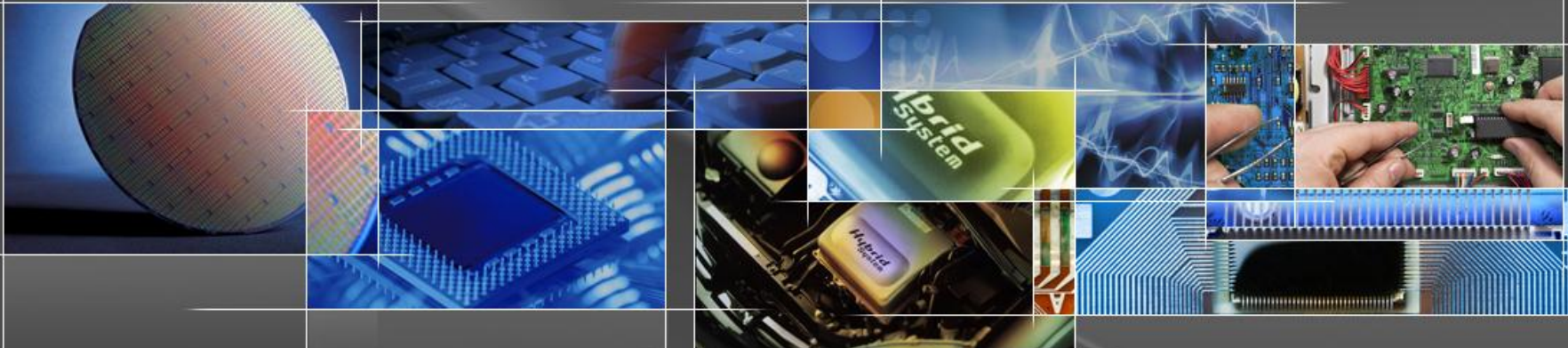


What is an SMU Instrument, and How Do You Decide Which One is Right for Your Application?

KEITHLEY

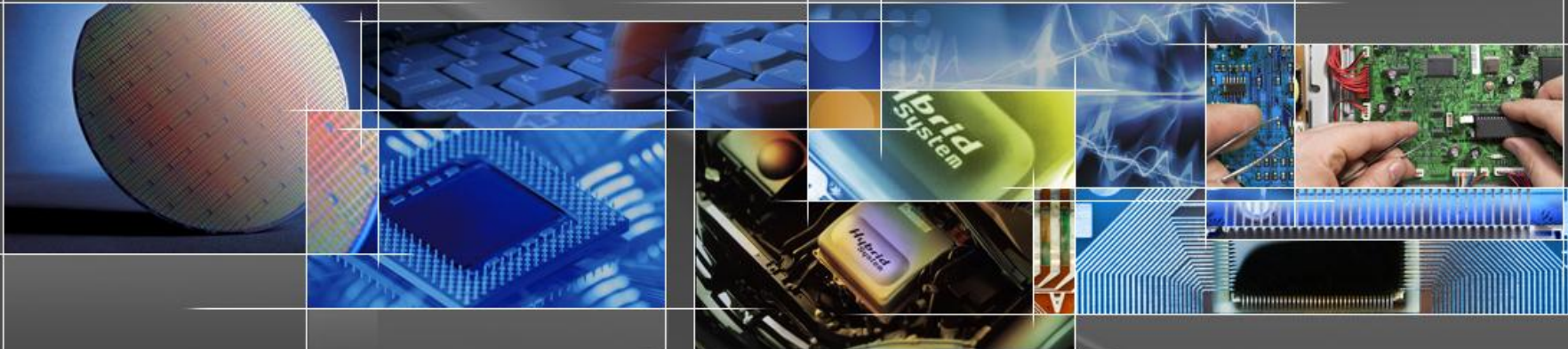


A GREATER MEASURE OF CONFIDENCE

Lishan Weng
Keithley Instruments, Inc.

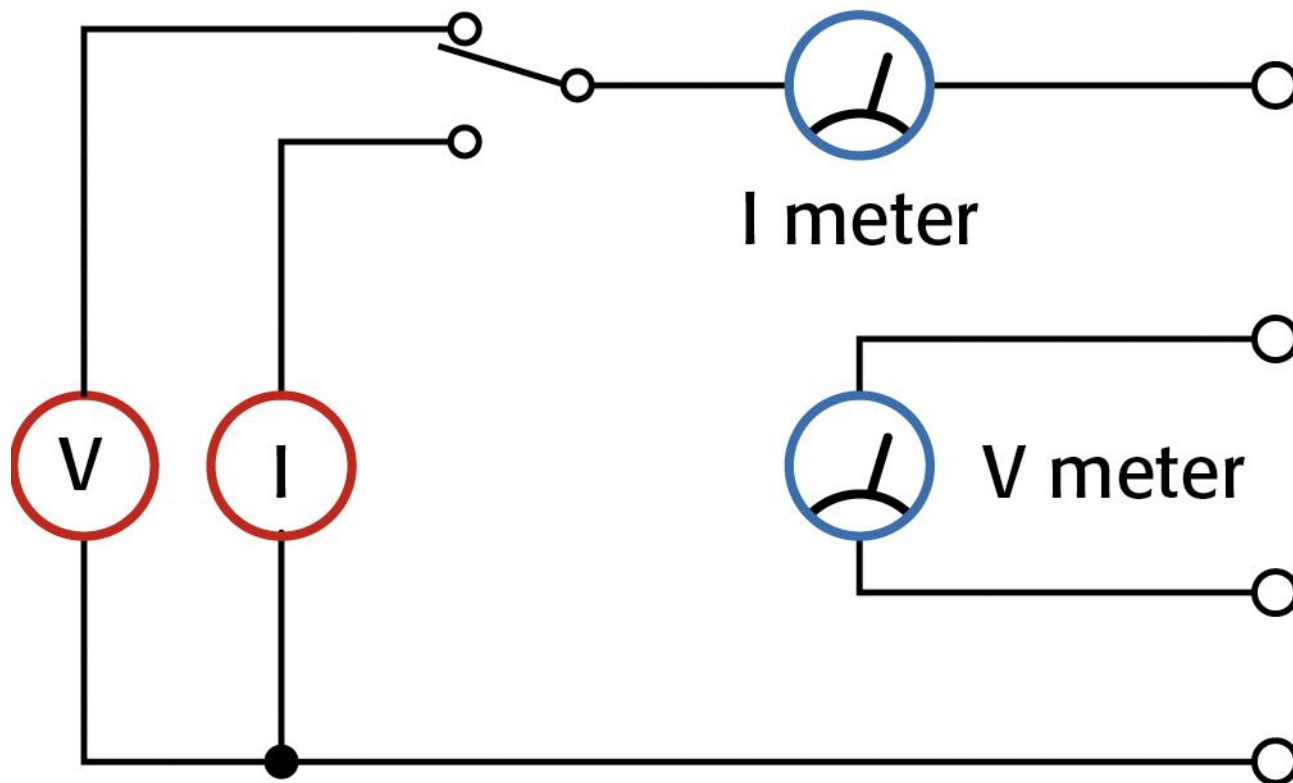
SMU Instrument Basics

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Basic SMU Topology





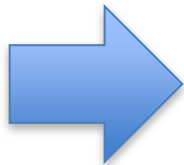
SMUs compared to Power Supplies



	2602A SourceMeter Instrument	Typical Power Supply
Speed		
Source/Measure Precision	10 μ A measurement uncertainty = 5nA	10 μ A measurement uncertainty = 2500nA
Voltage and Current Resolution	<p>Voltage</p> <p>Current</p>	<p>Voltage</p> <p>Current</p>
4 Quadrant Operation	<p>Source + Sink</p>	<p>Source Only</p>



SMUs compared to Power Supplies

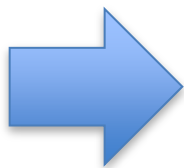


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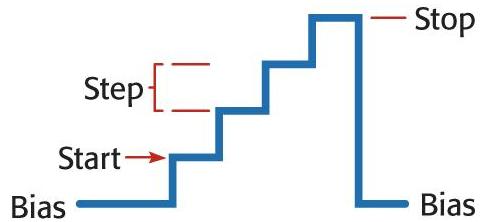


Built-in Sweeps

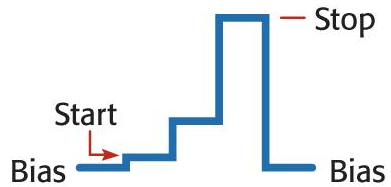
DC



Fixed Level

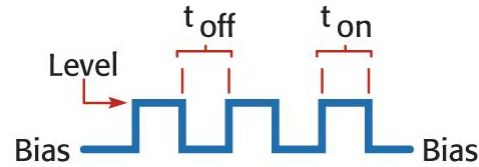


Linear Stair

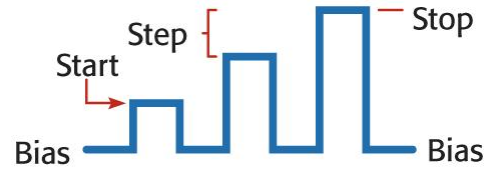


Logarithmic Stair

Pulse



Pulse

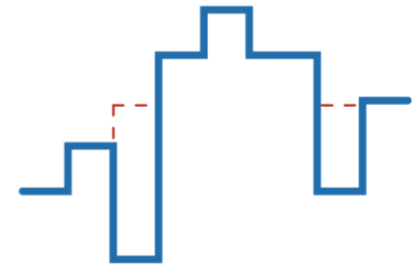


Linear Stair Pulse

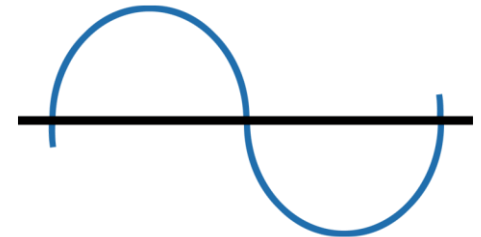


Logarithmic Stair Pulse

Custom



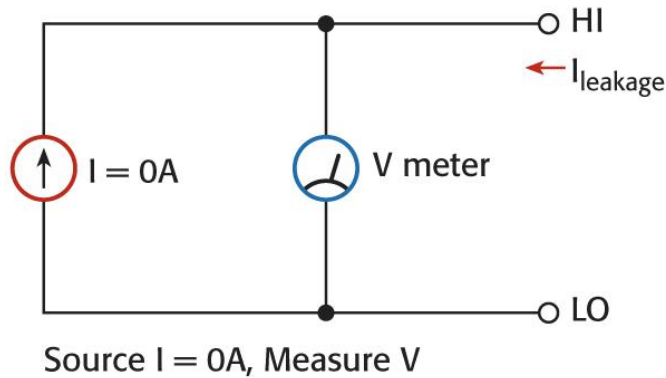
Arbitrary



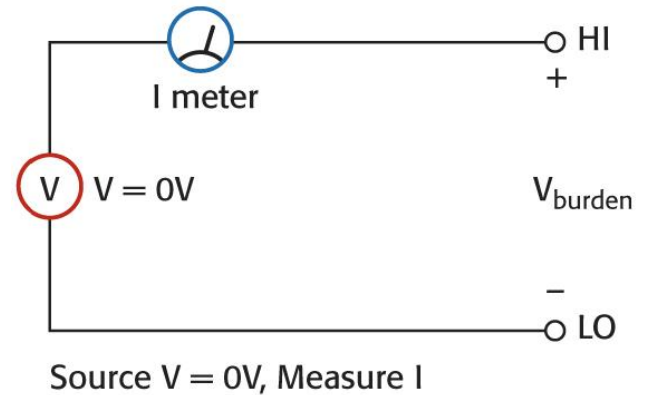
Sine Wave

SMUs compared to DMMs

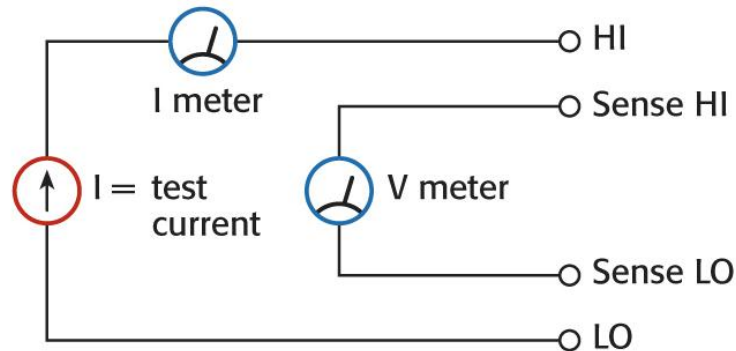
Voltmeter Configuration



Ammeter Configuration

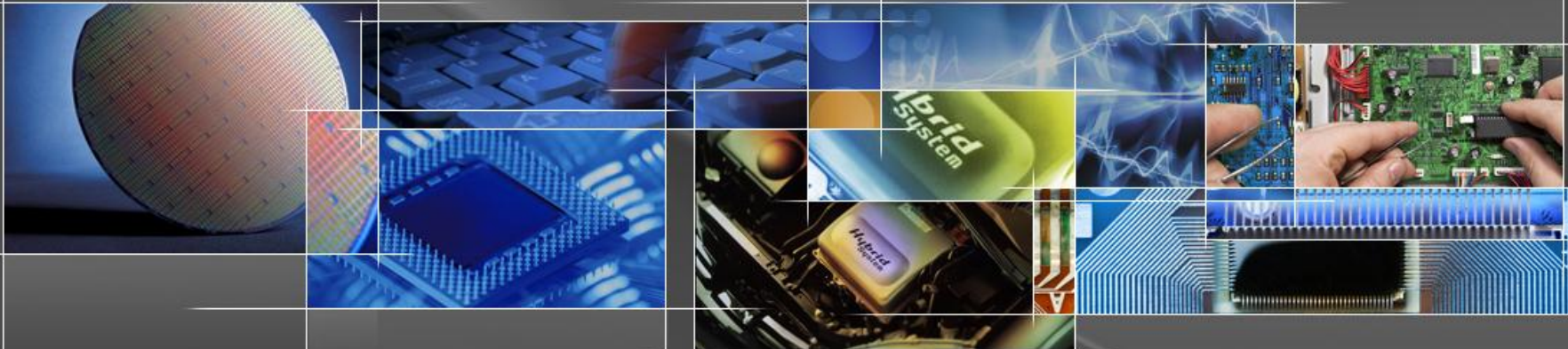


Ohmmeter Configuration

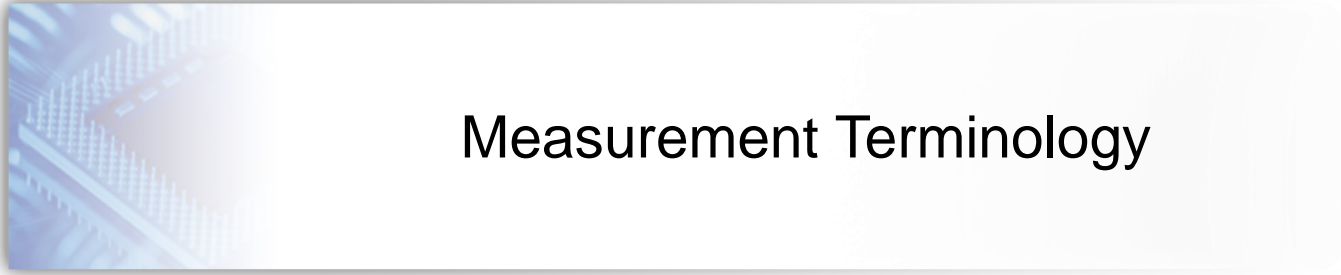


Measurement Terminology

KEITHLEY



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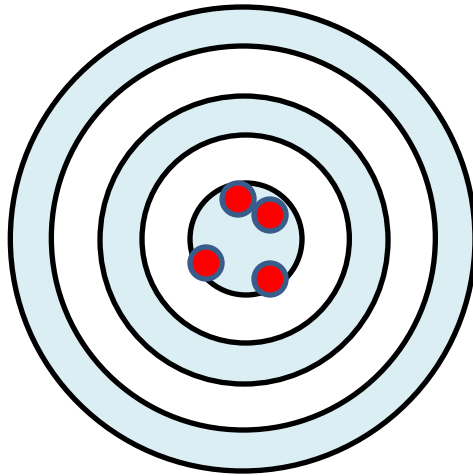
Measurement Terminology

- Accuracy
- Repeatability
- Resolution
- Sensitivity
- A/D Converter Integration Time (NPLC)

Measurement Terminology

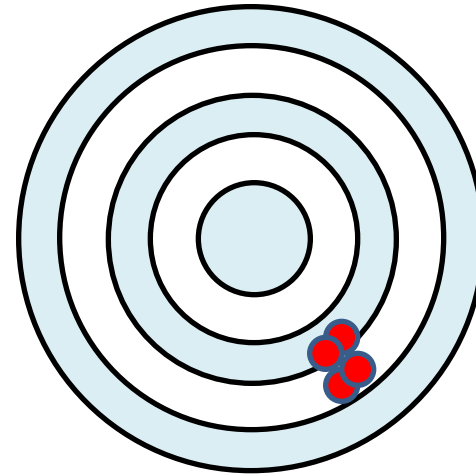


Accuracy



The closeness of agreement between the result of a measurement and its true value or accepted *standard value*.

Repeatability



The closeness of agreement between *successive* measurements carried out under the same conditions.



Measurement Terminology



Resolution

The smallest *portion* of the signal that can be observed.

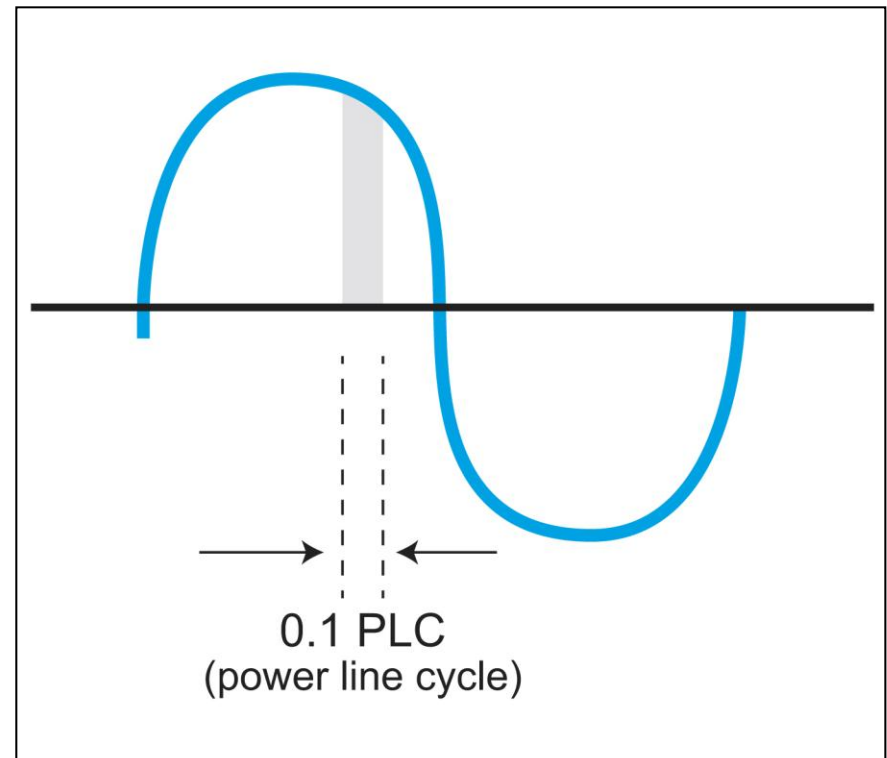
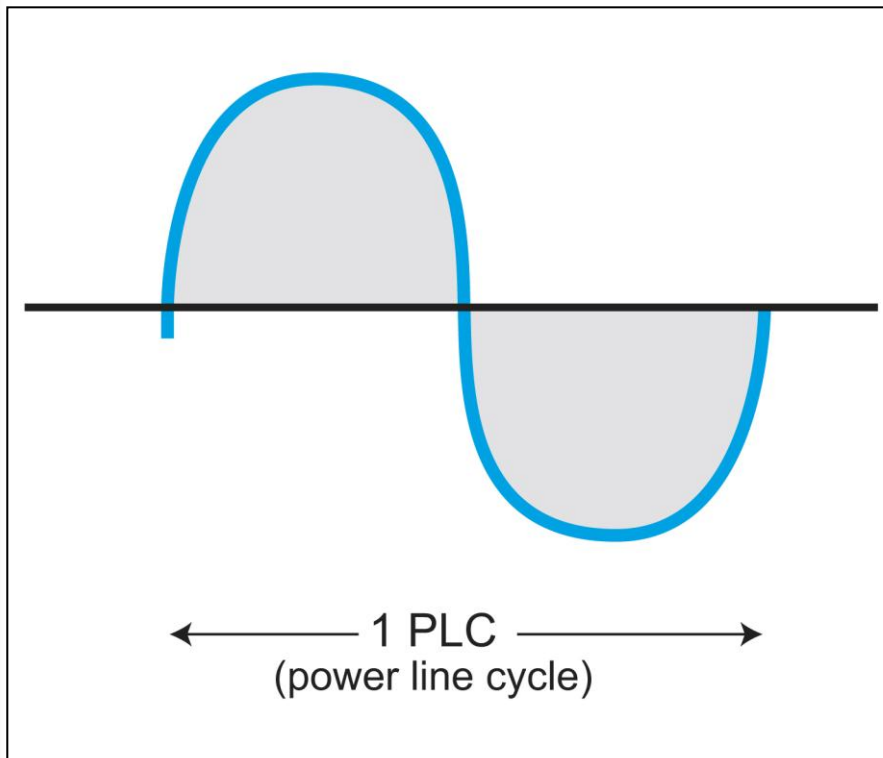
Sensitivity

The smallest *change* in the signal that can be detected.



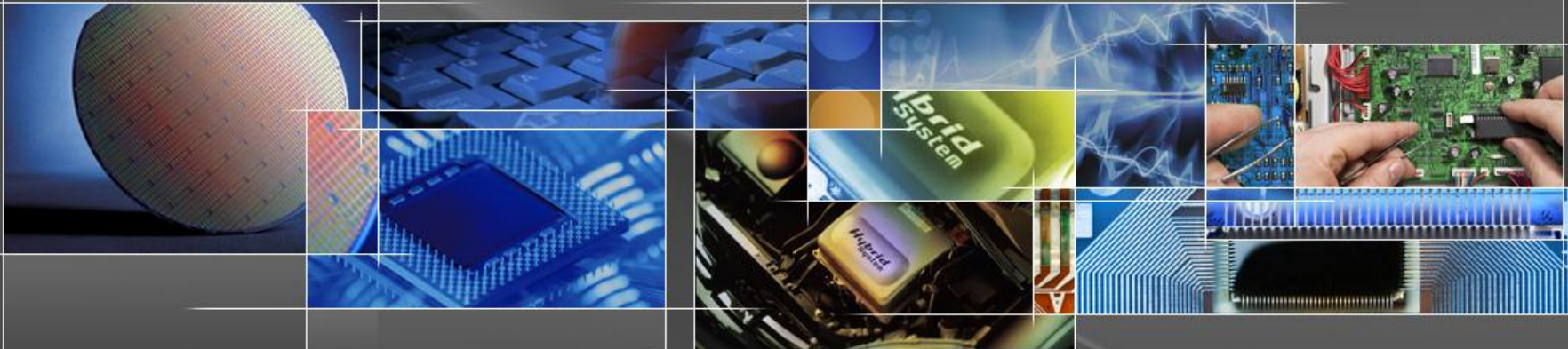


A/D Converter Integration Time (NPLC)



Key Considerations for Selecting a SMU Instrument

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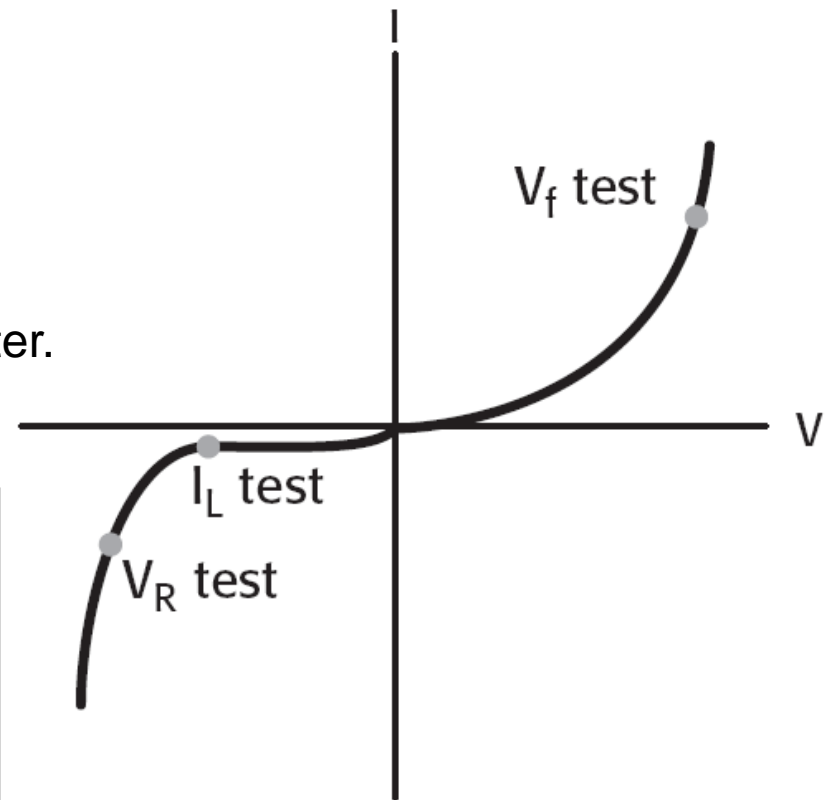
Key Considerations for Selecting a SMU Instrument

- System-level Speed / Throughput
- Source Resolution vs. Stability
- Measure Settling Time, Offset Error, Noise
- Cabling and Connections

System-level Speed / Throughput

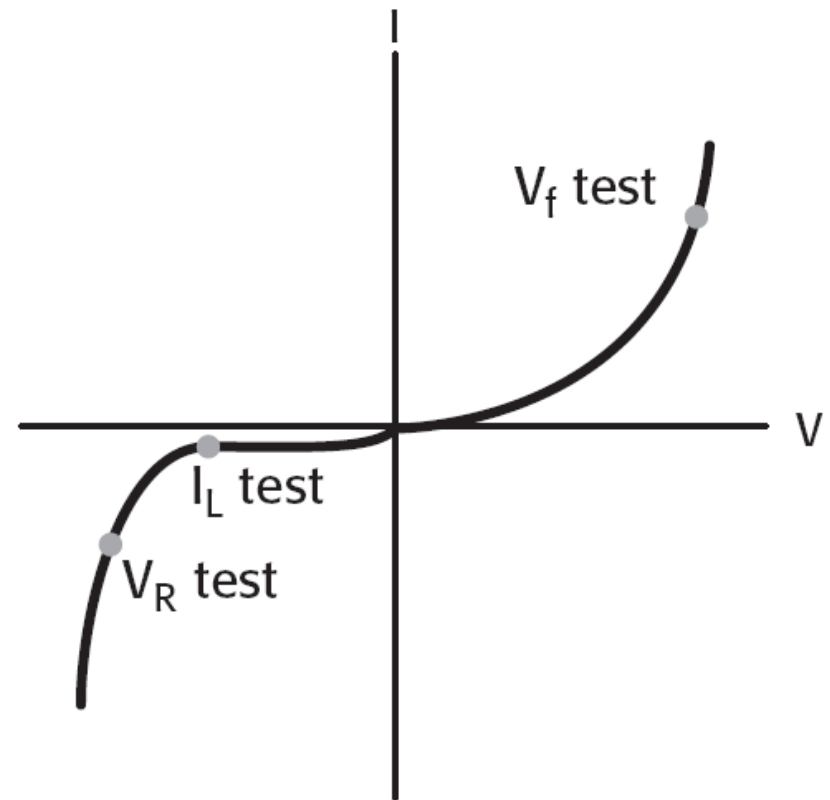
Example: Diode / LED Test

- Three Measurements
 - V_f – Forward Voltage
 - V_R – Reverse Breakdown Voltage
 - I_L – Reverse Leakage Current
- Measurements are compared against upper and lower limits for each parameter.



System-level Throughput Considerations

- Must consider and optimize all elements of speed:
 - Trigger In Time
 - Range Change Time
 - Function Change Time
 - Source Settling Time
 - A/D Converter (NPLC)
 - Measurement Speed
 - Trigger Out Time
 - Program Execution Time





Test Throughput: Actual Parts per Second

(more is better!)

	1 NPLC	0.1 NPLC	0.01 NPLC	0.001 NPLC	0.00048 NPLC
Non-Keithley SMU instrument	6.1	8.1	8.2	8.2	8.2
Keithley 2600A Series	13.3	33.2	37.8	38.2	N/A

Most accurate ←————→ Least accurate

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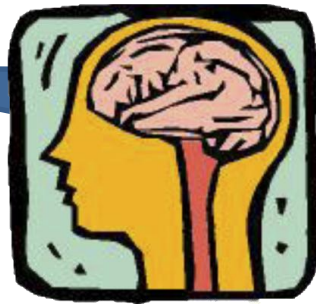
Most accurate ← → Least accurate



A SourceMeter running at 0.1 NPLC A/D conversion time is 4x faster and much more accurate than a SMU instrument running at 0.00048 NPLC

Keithley TSP[®] Technology

- The SourceMeter[®] SMU Instrument has embedded intelligence!



Keithley Model 2600A Series SourceMeter

Example TSP script:

```

for Voltage = 1,10 do
  smua.source.levelv = Voltage
  delay(1)
  Current = smua.measure.i()
  Resistance = Voltage / Current
  print ("Resistance=",Resistance)
End

```



Source Programming Resolution vs. Stability

Spec sheet (Programming Resolution):

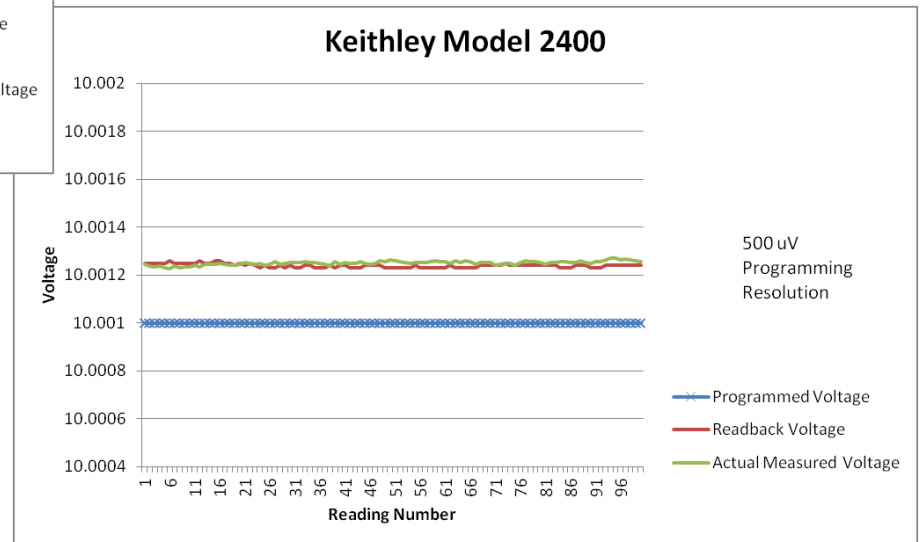
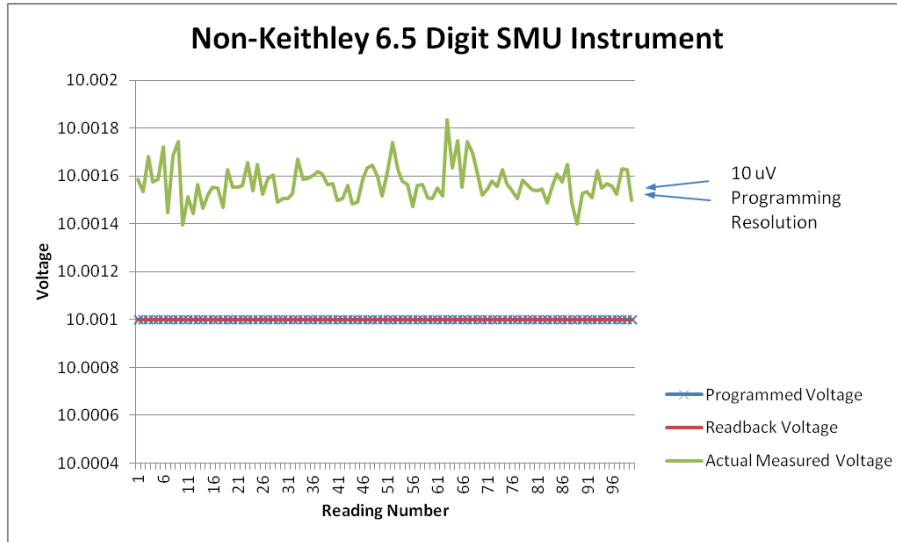
	Programming Resolution 20 V range
Non-Keithley 6.5 Digit SMU instrument	10 μ V
Keithley Model 2400	500 μ V

Actual Output (Stability):

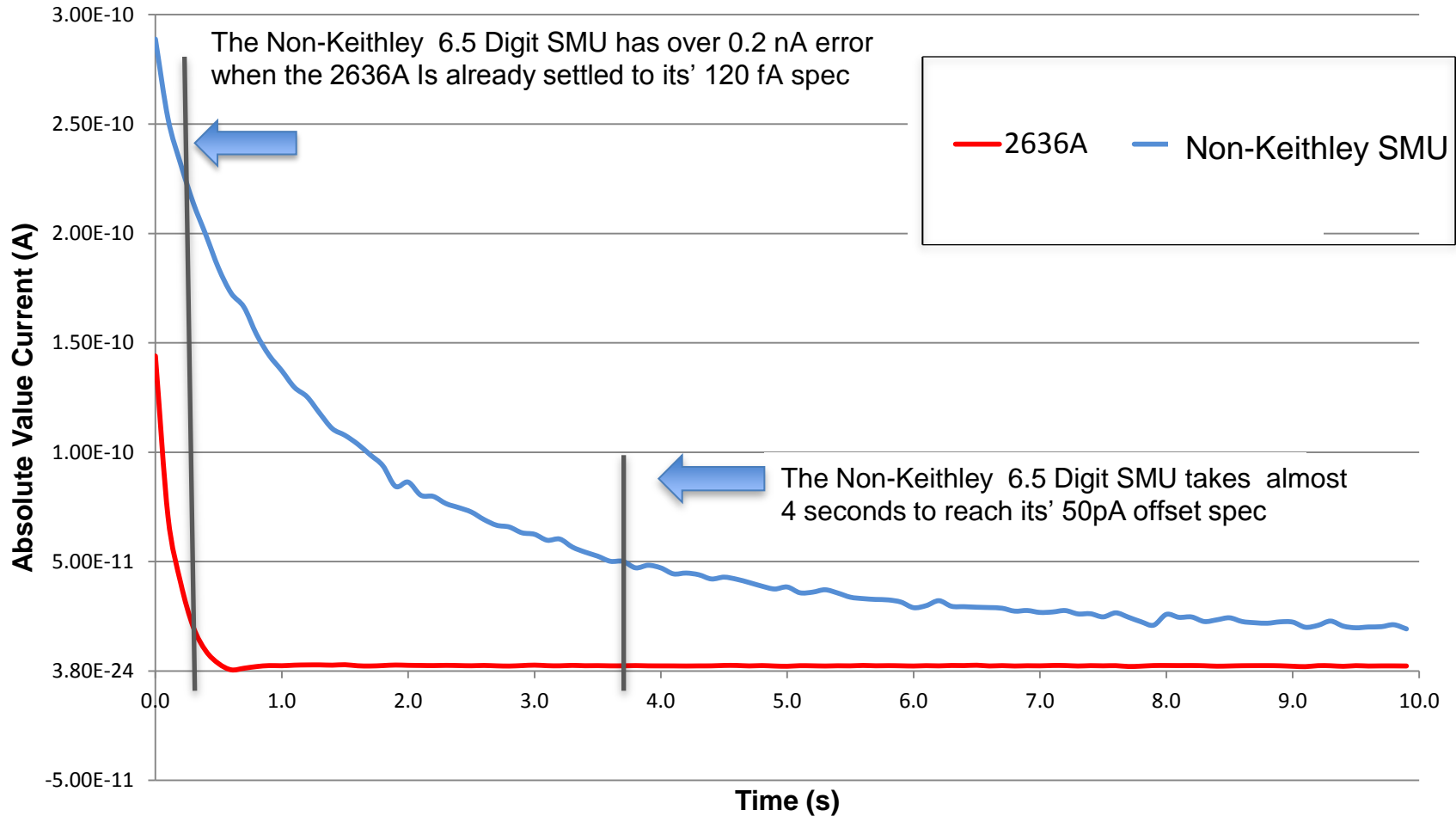
Source Value = 10.001V	Source Readback Displayed Value (pk-pk variation)	Actual Measured Value of Source Output (pk-pk variation)
Non-Keithley 6.5 Digit SMU instrument	0.0 μ V	438.7 μ V
Keithley Model 2400	30.0 μ V	42.9 μ V



Actual Source Performance: Programming Resolution vs. Stability



Open Circuit Offset Current at 200V: 10nA Range





Comparing Specifications and Performance

Spec table:

SMU	Lowest range	Total accuracy*	Resolution
Non-Keithley	10nA	$\pm (0.10\% + 50\text{pA})$	10fA
Keithley 2636A	100pA	$\pm (0.15\% + 120\text{fA})$	1fA

* Total accuracy = Gain accuracy (%) + Offset accuracy

Lowest Current Range

Non-Keithley
6.5 Digit SMU:

Keithley 2636A

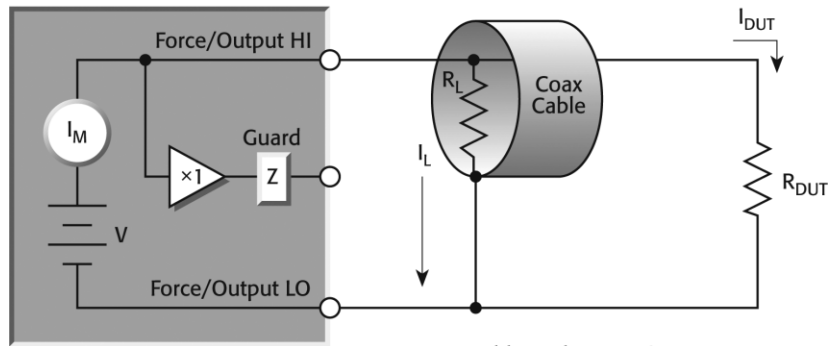
nA	pA	fA
10	50	00x
	100	120

Offset Accuracy Spec

Cable and Connection Considerations

Coax Cable

a) Unguarded Circuit

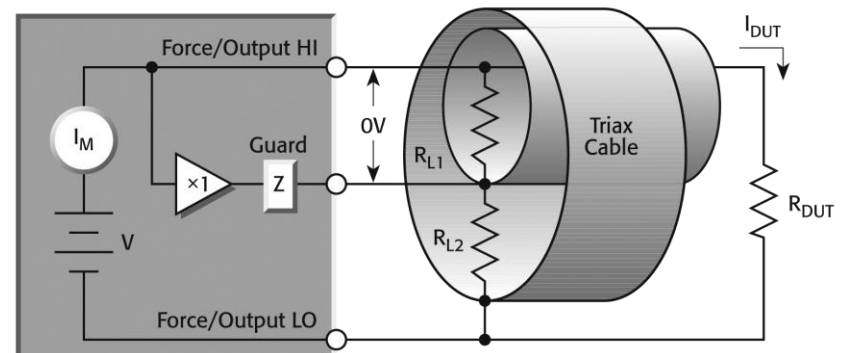


SMU

- R_L = Coax Cable Leakage Resistance
- I_L = Leakage Current
- R_{DUT} = Resistance of Device Under Test
- $I_M = I_{DUT} + I_L$

Triax Cable

b) Guarded Circuit



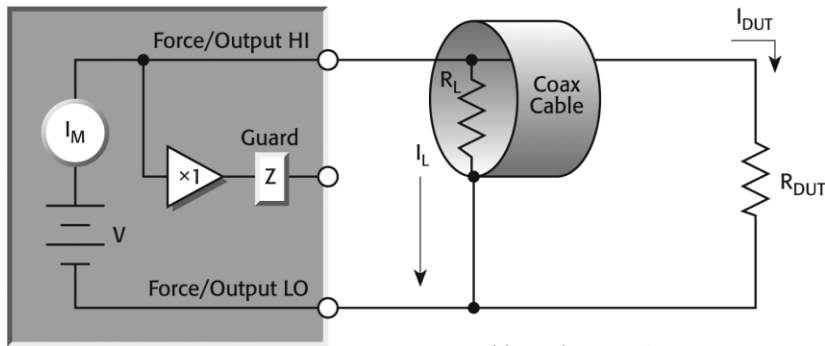
SMU

- R_{L1} = Triax Cable Inside Shield Leakage Resistance
- R_{L2} = Leakage Resistance Between Shields
- R_{DUT} = Resistance of Device Under Test
- $I_M = I_{DUT}$

Cable and Connection Considerations

Coax Cable

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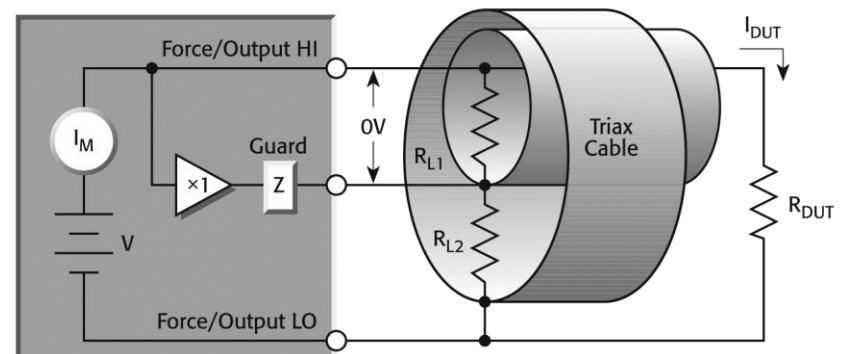


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 R_{L2} = Leakage Resistance Between Shields
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 $I_M = I_{DUT}$



Triax cables are included in the price of the 2635A and 2636A SourceMeter SMU Instruments

SourceMeter® Source Measurement Unit (SMU) Instruments

Industry Leading I-V Characterization & Test Tools



Feature	High Power SourceMeter Instruments (2651A, 2430)	Low Current SourceMeter Instruments (2635A/36A, 237, 6430)	Series 2600A System SourceMeter Instruments	Series 2400 Bench SourceMeter Instruments
# of Channels	1 (Optional Expansion to 32)	1 – 2 (Optional Expansion to 64)	1 – 2 (Optional Expansion to 64)	1
Current Max/Min	50A pulse / 1pA	10A pulse / 10aA	10A pulse / 1fA	5A / 10pA
Voltage Max/Min	100V / 1uV	1100V / 1uV	200V / 1uV	1100V / 1uV
DC Power	1100 - 2000W (pulse)	2 - 30W per channel	30 – 40W per channel	20 – 110W
Max readings/sec	38,500 1uSec / pt., 18-bit Digitizer	20,000	20,000	2,000
Interfaces	GPIB, LAN (LXI), RS-232, Digital I/O, TSP-Link® Channel Expansion Bus	GPIB, LAN (LXI), RS-232, Digital I/O, TSP-Link® Channel Expansion Bus	GPIB, LAN (LXI), RS-232, Digital I/O, TSP-Link® Channel Expansion Bus	GPIB, RS-232, Digital I/O
Connectors	Screw Terminal, Banana	Triax	Screw Terminal, Adaptors for Banana or Triax	Banana

Keithley is the Leader in SMU Instruments

- 20 patents issued for SMU-specific technology
- Numerous industry awards, including *R&D100*, Test of Time, Best in Test, Best Electronic Design, and more
- Thousands and thousands of customers
- Serving Semiconductor, Electronic Components, Optoelectronics, Automotive, Mil/Aero, Medical, Research & Education, and many more industries



**Series 2400
SourceMeter Instruments**



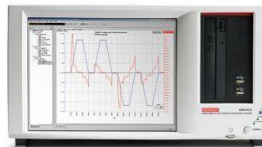
**Series 2600A System
SourceMeter Instruments**



Model 237 High-Voltage SMU



**Model 4200-SCS
Semiconductor Characterization System**



**S500 and S530
Parametric Test Systems**





SMU Instrument Reference Library

www.keithley.com

- Choosing the Optimal Source Measurement Unit (SMU) Instrument for Your Test and Measurement Application
- Rapidly Expanding Array of Test Applications Continues to Drive Source Measurement Unit Instrument Technology
- Precision Sourcing and Measurement Techniques for Applications from Semiconductor Research and Development to High Throughput Component Test

www.keithley.com/knowledgecenter

- Low Level Measurements Handbook: Precision DC Current, Voltage, and Resistance Measurements (Sixth Edition)

www.keithley.com/events/semconfs/webseminars

www.keithley.com/products/onlinedemo



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